

Application/Control No.	Applicant(s)/Patent under Reexamination		
09/770,366	DASIKA ET AL.		
Examiner	Art Unit		
Hanh Nguyen	2668		

SEARCHED				
Class	Subclass	Date	Examiner	
370	395.1	10/27/2005	HN	
_	222			
	535			
	536			
	537			
	352			
	389			
	419			
	470			
398	45			
	43			
	49			
	59			
	83			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
370	359				
	222				
398	45				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
east	10/27/2005	HN		